

two-dimensional device preparation process.

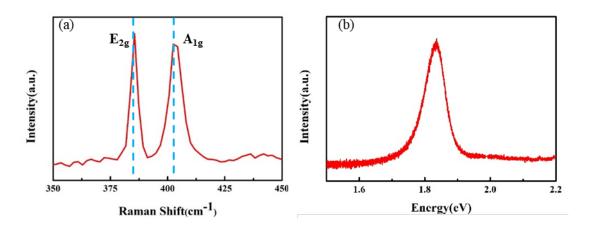
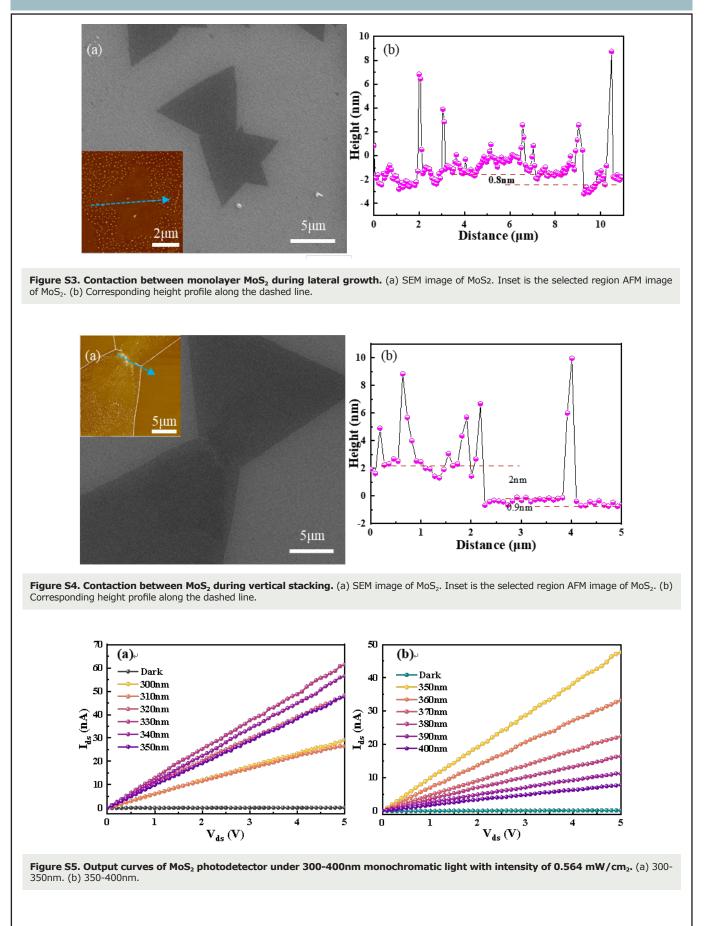


Figure S2. Raman spectroscopy and photoluminescence spectroscopy of MoS₂. (a) Raman spectroscopy. (b) Photoluminescence spectroscopy.

Table S1. Analysis of X-ray photoelectron spectroscopy

Element	Scanning peak/eV	Theoretical peak/eV	Peak area ratio	Theoretical ratio	Peak	Valence state
Мо	229.8	229.1	1:0.92	3:2	Mo 3d _{5/2}	Mo ⁴⁺
	233.0	232.3			Mo 3d _{3/2}	
S	162.6	162.1	1:0.47	2:1	S 2p _{3/2}	S ²⁻
	163.9	163.2			S 2p _{1/2}	



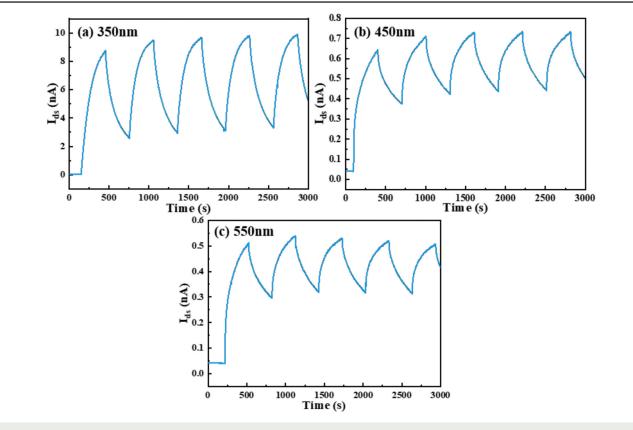


Figure S6. I-t curves of MoS_2 photodetector under different wavelength with intensity of 0.564 mW/cm2. (a)350nm. (b)450nm. (c)550nm.

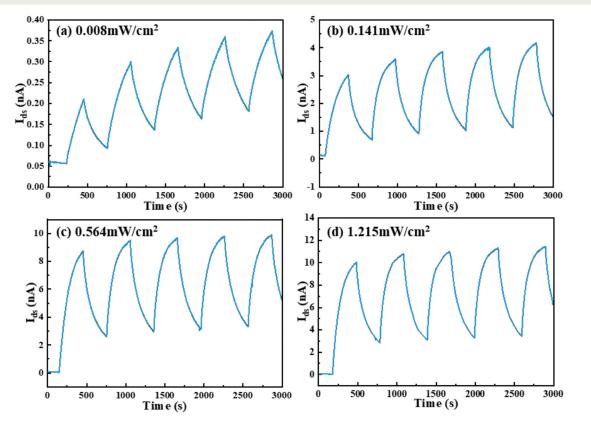


Figure S7. I-t curves of MoS_2 photodetector under different light intensities at 350nm wavelength. (a) 0.008 mW/cm2. (b) 0.141 mW/cm2. (c) 0.564mW/cm2 (b) 1.215mW/cm2.